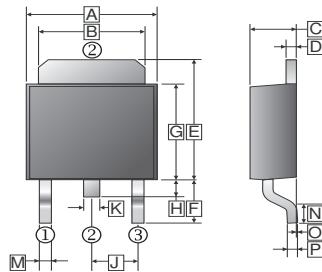
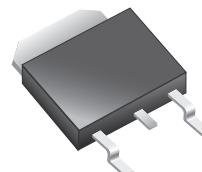


RoHS Compliant Product
A suffix of "-C" specifies halogen free

DESCRIPTION

The SSD50N03-C is the highest performance trench N-ch MOSFETs with extreme high cell density, which provide excellent R_{DS(on)} and gate charge for most of the synchronous buck converter applications.

TO-252(D-Pack)



FEATURES

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

MARKING



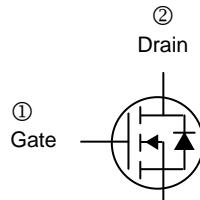
PACKAGE INFORMATION

Package	MPQ	Leader Size
TO-252	2.5K	13 inch

REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	6.3	6.9	J	2.3	REF.
B	4.95	5.53	K	0.89	REF.
C	2.1	2.5	M	0.45	1.14
D	0.4	0.9	N	1.55	Typ.
E	6	7.7	O	0	0.15
F	2.90	REF.	P	0.58	REF.
G	5.4	6.4			
H	0.6	1.2			

ORDER INFORMATION

Part Number	Type
SSD50N03-C	Lead (Pb)-free and Halogen-free



ABSOLUTE MAXIMUM RATINGS

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V _{DS}	30	V
Gate-Source Voltage	V _{GS}	±20	V
Continuous Drain Current, @V _{GS} =10V ¹	T _C =25°C	51	A
	T _C =100°C	36	
	T _A =25°C	12.4	
	T _A =70°C	10.3	
Pulsed Drain Current ²	I _{DM}	110	A
Single Pulse Avalanche Energy ³	E _{AS}	128	mJ
Single Pulse Avalanche Current	I _{AS}	16	A
Total Power Dissipation ⁴	T _C =25°C	P _D	W
Operating Junction and Storage Temperature Range	T _J , T _{STG}	-55~150	°C
Thermal Resistance Rating			
Maximum Thermal Resistance Junction-Case ¹	R _{θJC}	3.05	°C/W
Maximum Thermal Resistance Junction-ambient ¹	R _{θJA}	62.5	°C/W

ELECTRICAL CHARACTERISTICS ($T_J=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Conditions
Drain-Source Breakdown Voltage	V_{DSS}	30	-	-	V	$V_{GS}=0$, $I_D=250\mu\text{A}$
Gate-Threshold Voltage	$V_{GS(\text{th})}$	1	-	2.5	V	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$
Forward Transconductance	g_{fS}	-	38	-	S	$V_{DS}=5\text{V}$, $I_D=30\text{A}$
Gate-Source Leakage Current	I_{GSS}	-	-	± 100	nA	$V_{GS}= \pm 20\text{V}$
Drain-Source Leakage Current	I_{DSS}	-	-	1	μA	$V_{DS}=24\text{V}$, $V_{GS}=0$
$T_J=55^\circ\text{C}$		-	-	5		
Static Drain-Source On-Resistance ⁴	$R_{DS(\text{ON})}$	-	-	9	$\text{m}\Omega$	$V_{GS}=10\text{V}$, $I_D=30\text{A}$
		-	-	13.5		$V_{GS}=4.5\text{V}$, $I_D=15\text{A}$
Total Gate Charge	Q_g	-	12.6	-	nC	$I_D=15\text{A}$ $V_{DS}=15\text{V}$ $V_{GS}=4.5\text{V}$
Gate-Source Charge	Q_{gs}	-	4.2	-		
Gate-Drain ("Miller") Change	Q_{gd}	-	5.1	-		
Turn-on Delay Time	$T_{d(\text{on})}$	-	4.6	-	nS	$V_{DD}=15\text{V}$ $I_D=15\text{A}$ $V_{GS}=10\text{V}$ $R_D=3.3\Omega$
Rise Time	T_r	-	12.2	-		
Turn-off Delay Time	$T_{d(\text{off})}$	-	26.6	-		
Fall Time	T_f	-	8	-		
Input Capacitance	C_{iss}	-	1317	-	pF	$V_{GS}=0$ $V_{DS}=15\text{V}$ $f = 1.0\text{MHz}$
Output Capacitance	C_{oss}	-	163	-		
Reverse Transfer Capacitance	C_{rss}	-	131	-		
Guaranteed Avalanche Characteristics						
Single Pulse Avalanche Energy ⁵	E_{AS}	32	-	-	mJ	$V_{DD}=25\text{V}$, $L=1\text{mH}$, $I_{AS}=8\text{A}$
Source-Drain Diode						
Continuous Source Current ¹	I_s	-	-	51	A	
Pulsed Source Current ²	I_{SM}	-	-	110		
Diode Forward Voltage ⁴	V_{SD}	-	-	1.2	V	$I_s=1\text{A}$, $V_{GS}=0$
Reverse Recovery Time	T_{rr}	-	9.2	-	nS	$I_F=30\text{A}$, $dI/dt=100\text{A}/\mu\text{s}$ $T_J=25^\circ\text{C}$
Reverse Recovery Charge	Q_{rr}	-	2	-		

Notes:

1. The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
2. Pulse width limited by maximum junction temperature , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$.
3. The EAS data shows Max. rating . The test condition is $V_{DD}=25\text{V}$, $V_{GS}=10\text{V}$, $L=1\text{mH}$, $I_{AS}=16\text{A}$.
4. The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
5. The Min. value is 100% EAS tested guarantee.

CHARACTERISTIC CURVES

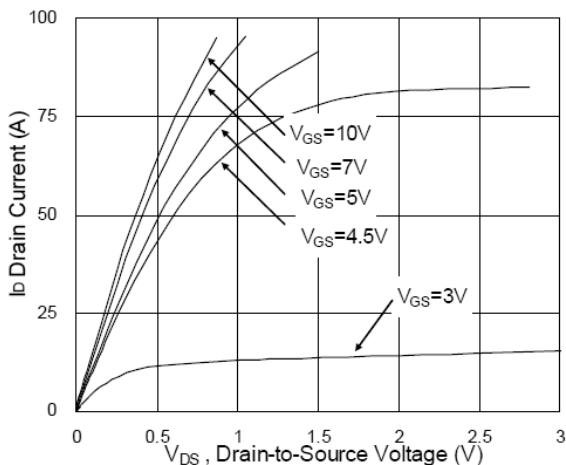


Fig.1 Typical Output Characteristics

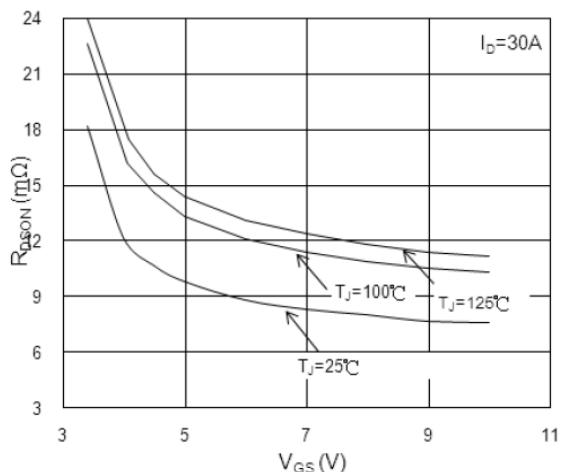


Fig.2 On-Resistance vs. G-S Voltage

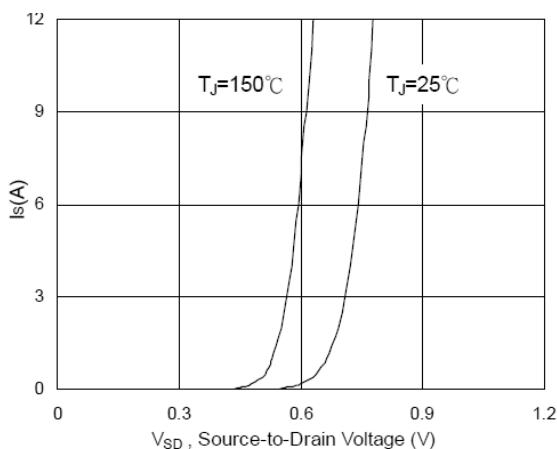


Fig.3 Forward Characteristics of Reverse

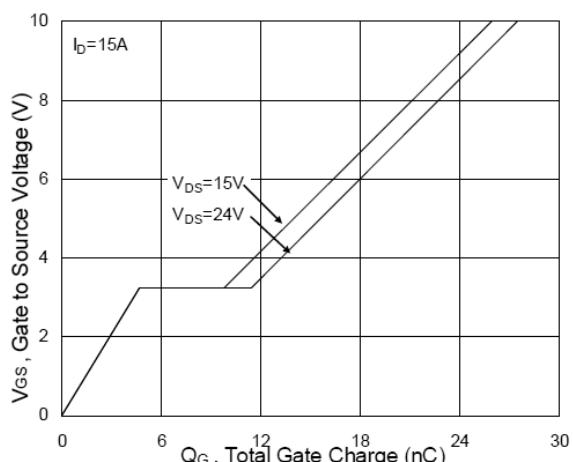


Fig.4 Gate-Charge Characteristics

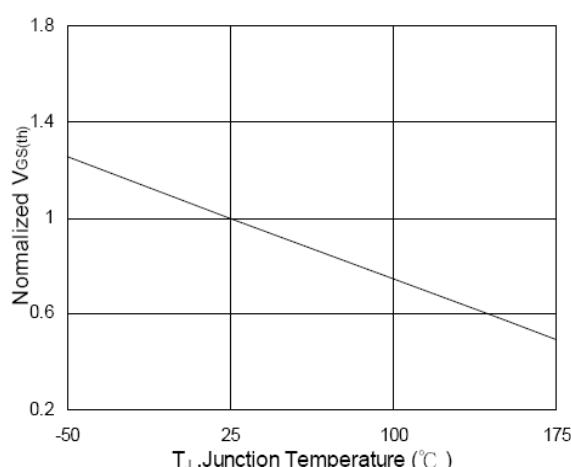


Fig.5 Normalized $V_{GS(th)}$ vs. T_J

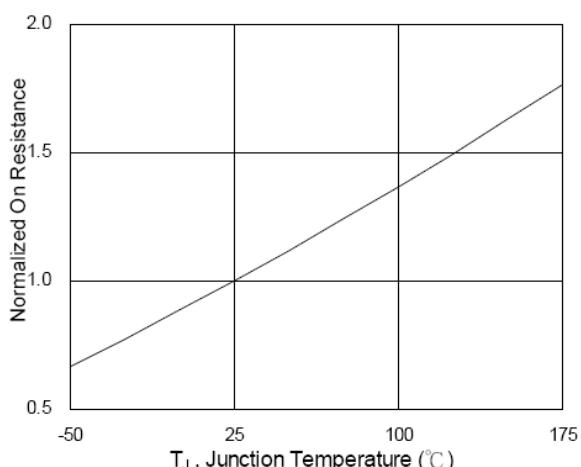


Fig.6 Normalized $R_{DS(on)}$ vs. T_J

CHARACTERISTIC CURVES

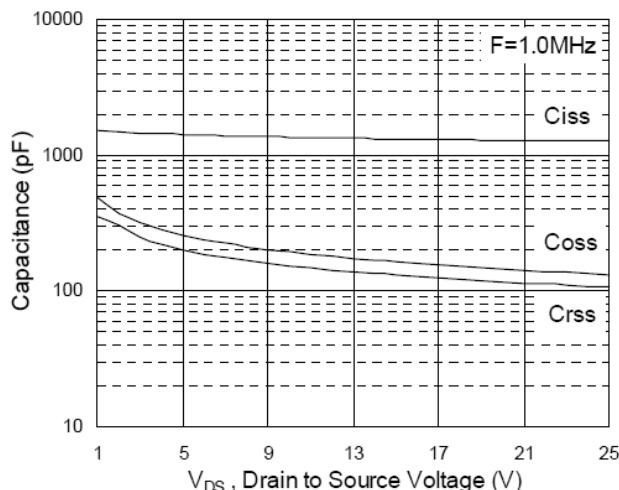


Fig.7 Capacitance

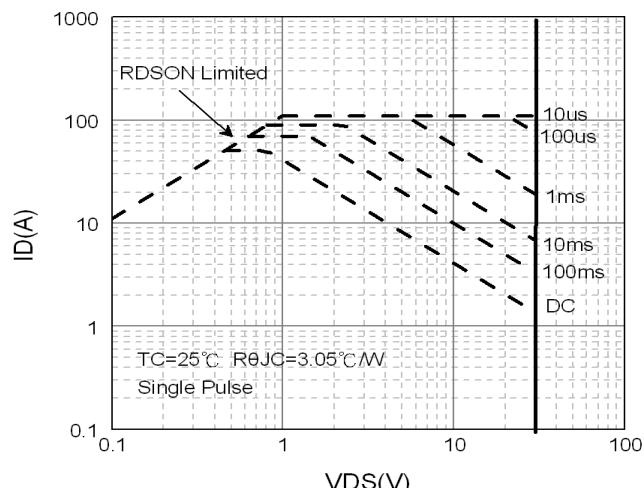


Fig.8 Safe Operating Area

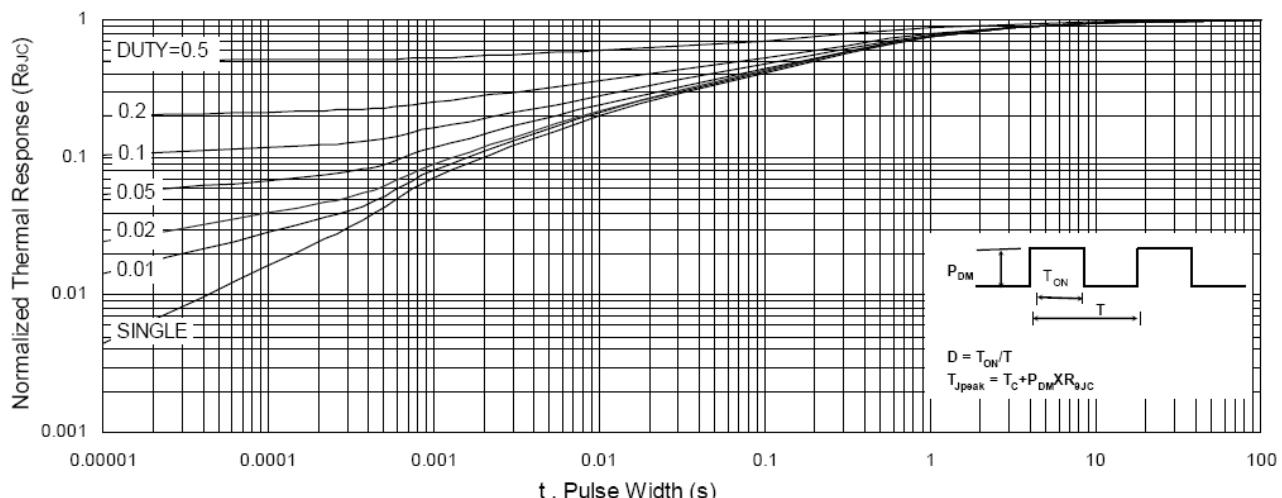


Fig.9 Normalized Maximum Transient Thermal Impedance

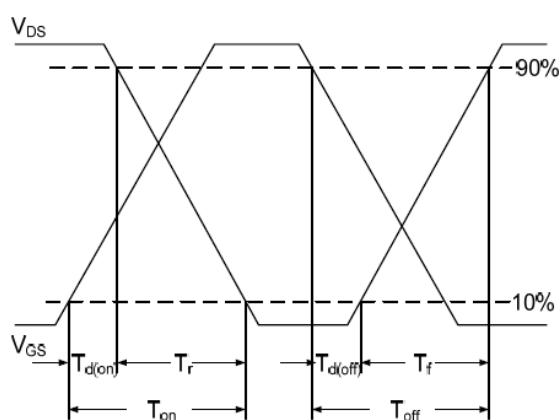


Fig.10 Switching Time Waveform

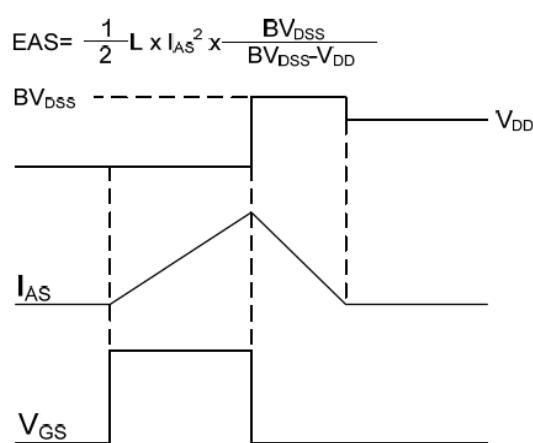


Fig.11 Unclamped Inductive Switching Waveform